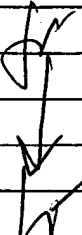


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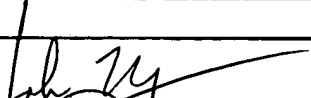
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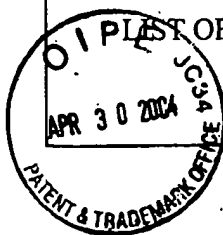
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V	6,393,894	05/2002	Bonne et al.			
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	DE 2 934 566 A1	03/19/81	Germany	Abstract
	DE 32 34 146 A1	03/15/84	Germany	Abstract
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